

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 203870US6		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Kenji NAKAGAWA, et al.			
		FILING DATE		Herewith		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
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	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO	
<i>Afr</i>	AO	2000-168896	6/20/00	Japan (w/ English Abstract)		X	
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
	AX						
	AY						
	AZ						
Examiner	<i>A. Turner</i>				Date Considered <i>9-9-03</i>		

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 203870US6	SERIAL NO. 09/883,997		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Kenji NAKAGAWA, et al.			
				FILING DATE June 20, 2001	GROUP 3723		
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
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	AG						
	AH						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO	
AKr	AI	2-162011 ✓	06/21/90	JAPAN (with English Abstracts)		X	
AKr	AJ	2-206539 ✓	08/16/90	JAPAN (with English Abstracts)		X	
ASr	AK	4-046638 ✓	02/17/92	JAPAN (with English Abstracts)		X	
ASr	AL	4-154550 ✓	05/27/92	JAPAN (with English Abstracts)		X	
AKr	AM	4-253690 ✓	09/09/92	JAPAN (with English Abstracts)		X	
AKr	AN	4-279497 ✓	10/05/92	JAPAN (with English Abstracts)		X	
AKr	AO	10-194388 ✓	07/28/98	JAPAN (with English Abstracts)		X	
AKr	AP	10-194389 ✓	07/28/98	JAPAN (with English Abstracts)		X	
AKr	AQ	60-230844 ✓	11/16/85	JAPAN (with English Abstracts)		X	
AKr	AR	62-46434 ✓	10/02/87	JAPAN (with English Abstracts)		X	
ASr	AS	62-94543 ✓	05/01/87	JAPAN (with English Abstracts)		X	
AKr	AT	2000-326395 ✓	11/28/2000	JAPAN (with English Abstracts)		X	
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
	AX						
	AY						
	AZ						
Examiner	<i>A. Thomas</i>				Date Considered 9-9-03		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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